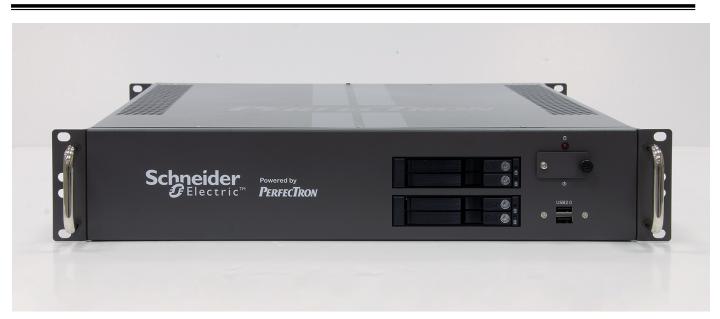


SCH401 PERFECTRON SYSTEM Reliability/Environment Test Plan

Product Manager	H/W Leader	System Engineer	Testing Engineer	
Stanley	Jason	Darren	Marc	







Version History				
Document Release	Date	Change Item	Remarks	
V1.0	7/19/2021	Preliminary release		



	System Configuration				
Motherboard	SUPERMICRO X12SCZ-F				
CPU	Intel [®] Core [™] i9-10900TE Processor 1.8 GHz				
РСН	Intel W480				
Memory	InnoDisk 8GB SOD DDR4 2133				
SATA port1	SSD 1TB				
LAN1	Intel®i219 LM GbE LAN				
LAN2	Intel® i210 GbE LAN				

	System Test Items Configuration _ Test Results Definition					
No.	T 4 14	Otre	Syst	em Sample		
INO.	Test Item	Qty	No.1	Remark		
1.	DC Input Voltage Function Test	1	PASS			
2.	IO Function Test	1	PASS			
3.	Operation System & Drivers Test	1	PASS			
4.	Power Consumption	1	PASS			
5.	I/O Integrated Stress Test	1	PASS			
6.	Temperature Alternate Operation Test	1	PASS			
7.	High Temperature Operating Test	1	PASS			
8.	High Temperature and Humidity Operating Test	1	PASS			
9.	Low Temperature Operation Test	1	PASS			
10.	High Temperature Power ON/OFF Test	1	PASS			
11	Low Temperature Power ON/OFF Test	1	PASS			
12	Thermal Measurement	1	PASS			



System Reliability/Environment Test table of Contents

- 1. DC Input Voltage Fluctuation Test
- 2. Power Consumption
- 3. Operation System & Drivers Test
- 4. Power Consumption
- 5. I/O Integrated Stress Test
- 6. Temperature Alternate operation Test
- 7. High Temperature Operating Test
- 8. High Temperature and Humidity Operating Test
- 9. Low Temperature Long Thermal Operation Test
- 10. High Temperature Power ON/OFF Test
- 11. Low Temperature Power ON/OFF Test
- 12. Thermal Measurement



Test Purpose	To evaluate the influence on the EUT under voltage fluctuation from the DC power Source	Test Result	PASS				
Test Equipment	DC power source: GWINSTEK PSW 80-13.5 Passmark USB3.0 Plug						
Quantity Tested	Minimum 1 Set						
Test Condition	Test Software: Passmark BURN-IN Test Program under Microsoft Windo Test Procedure: 1. Adjust DC power source to upper limit (VDC+5%) 2. Turn on the system and perform the function test with 1 of 1 hour at least 3. Check the functions of the system and record it 4. Change DC power source to lower limit (VDC-5%) 5. Repeat steps 2~3	00% loading fo					
Test Criteria	Criteria All units must be pass 1 hour Burn-In test program, without any error occur. The EUT must be no damage or safety problem occurred.						

1. DC Input Voltage Fluctuation Test



	1. DC power Adaptor
Test Log / Photo	2. Test Log
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2. IO Function Test

Item		Criteria	Result	Note
SATA Port 1		SATAIII Onboard SSD device Run PassMark 20 minutes with all disks	Pass	
		can use any USB device	Pass	
USB1		Loopback Plugs for USB 2.0 Trouble shooting and Testing	Pass	
LICDA		can use any USB device	Pass	
USB2		Loopback Plugs for USB 2.0 Trouble shooting and Testing	Pass	
		can use any USB device	Pass	
USB1		Loopback Plugs for USB 3.0 Trouble shooting and Testing	Pass	
LICDO		can use any USB device	Pass	
USB2		Loopback Plugs for USB 3.0 Trouble shooting and Testing	Pass	
LICD2		can use any USB device	Pass	
USB3		Loopback Plugs for USB 3.0 Trouble shooting and Testing	Pass	
		can use any USB device	Pass	
USB4		Loopback Plugs for USB 3.0 Trouble shooting and Testing	Pass	
	DP		Pass	
Display output	DP	Check work well	Pass	
	DVI		Pass	
VGA		Check work well	Pass	
LAN port1		Intel i219 LAN Function Test	Pass	
LAN port2		Intel i210 LAN Function Test	Pass	
IPMI		Check work well	Pass	
Power SWITCH		Check work well	Pass	
Power Led		Check work well	Pass	
HDD Led		Check work well	Pass	
LAN1/LAN2 LE	D	Check work well	Pass	
DC in		Check work well	Pass	

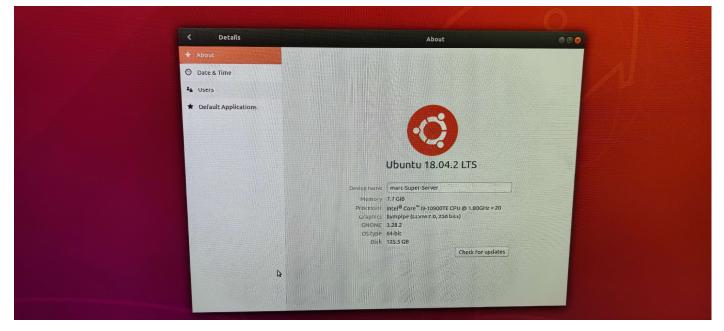


Operation System & Drivers Test

Publisher	Package & Version	DUT-1	Note
Microsoft OS	UEFI boot	Pass	
Microsoft OS	Microsoft Windows 10 64Bit	Pass	
Linux	Ubuntu18.04	Pass	

Driver and Application software	Version / Details	DUT-1	Note
INF	10.1.18415	Pass	
VGA	27.20.100.8336	Pass	
LAN	25.0.0.0	Pass	
ME	14.0.39.1339	Pass	
ASPEED	9.0.10.102		

UBUNTU18.04





Display Function Test

DP Test							
	2. Check display	. Use 800x600 1024x768 1280x720(or highest solution) and 16&32 bit to test display correctly. . Check display with test pattern . check display can nothas any cross-color, water wave, and ghost.					
resolution	800x600, 60Hz	800x600, 75Hz	1024x768, 60Hz	1024x768, 75Hz	1280x720, 60Hz	1280x720, 75Hz	1920x1080, 60Hz
DP1	PASS	PASS	PASS	PASS	PASS	PASS	PASS
DP2	PASS	PASS	PASS	PASS	PASS	PASS	PASS
DVI	PASS	PASS	PASS	PASS	PASS	PASS	PASS
VGA	PASS	PASS	PASS	PASS	PASS	PASS	PASS

			Resolution t	est
Monitor	ASUS 27" P	B278Q , Maxim	num resolution : 2560 x 1440	
Model	ASUS 23" PA	A238 , Maximur	m resolution $: 1920 \ge 1080$	
Resolution	D	P1	DP2	DVI
1024 x 768		\checkmark	✓	\checkmark
1280 x 1024		\checkmark	✓	\checkmark
1366 x 768		\checkmark	✓	\checkmark
1920 x 1080		\checkmark	✓	\checkmark
1920 x1200		\checkmark	✓	\checkmark
2560 x 1440		\checkmark	\checkmark	\checkmark



4. Power Consumption

Test Purpose	To measure power consumption of the EUT during operation/suspend mode/power off mode
Quantity Tested	Minimum 1 Set
Test Procedure	 Turn on the power source and set the output voltage frequency following to the test specification Connect the Power Meter between EUT and power source Connect maximum quantity of external devices on all I/O (ex. USB, COM, etc), and have the full loading status on each device Turn on the EUT and set the EUT on each consumption mode Measure and record the power consumption value shown on Power Meter as Watt
Test Criteria 1. The Max. power consumption value must not exceed the output ability of used power supply, the derating while in high temperature environment must also to be considered 2. By following the EuP LOT 6 requirement, the power consumption of the standby mode limited 1.0 Watt (for w/o WOL model) and 1.7Watt (for w/ WOL model)	

Item	Device Information (Full load)		
CPU	Intel [®] Core [™] i9-10900TE Processor 1.8 GHz		
РСН	Intel W480		
Memory	InnoDisk 8GB SOD DDR4 2133		
SATA port 1	SSD 1TB		
DP	Dell U2312		
LAN1 ~ LAN2	LAN (Loopback)		
USB3~USB6	1A 水泥電阻		
USB1~USB2	USB Keyboard & Mouse		
Operating System	Windows 10 Professional 64-bit		
Test Equipment	FSP060-DBAE1		
Test Software	Burnin test v9.0 、 、 IntelBurnTest 1.9 XTU CPU STRESS,FU MARK		

Power Measure (Full loading)

Model	Test Voltage	Voltage	Current	Power consumption	
I9-10900TE	70V DC	69.96V DC	2.34A	163.7W	

Power Measure (Hearvy load)								
Item	Voltage/ Condition	Win Idle	S3	S4	S5	Current	Power consumption	Note
Core I9-10900TE Processor	70 V	0.27A	0.11 A	0.11A	0.11 A	1.16 A	81.2W	



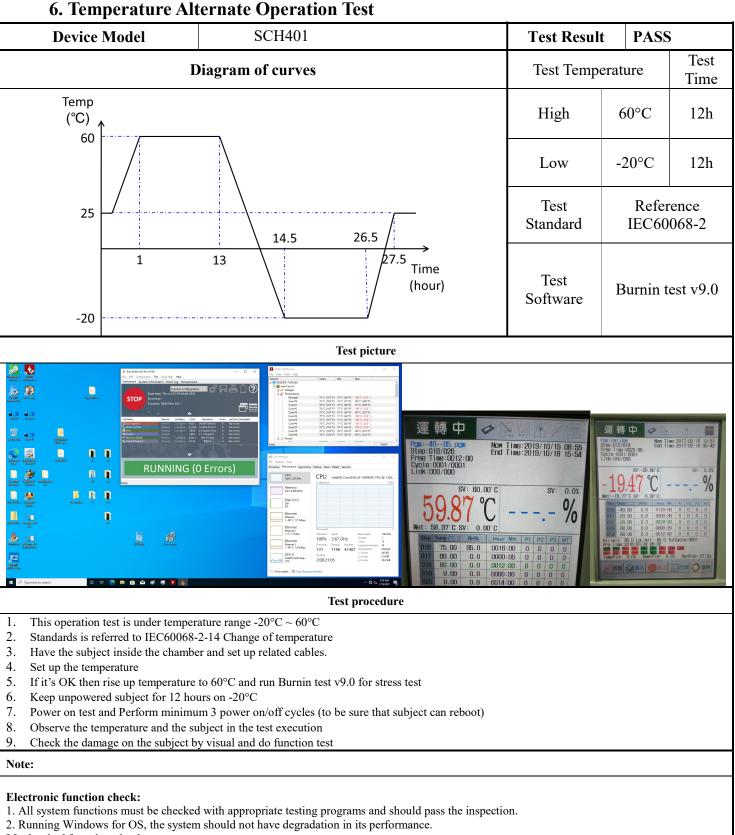
5. I/O Integrated Stress Test

System configu	ration							
CPU Intel® Core™ i9-10900TE Processor 1.8 GHz								
RAM1		InnoDisk 8GB SOD DDR4 2133						
O.S.		Windows 10 SP1 Ultimate E	dition 64bit					
Temperature		Room temperature						
Testing Utility	and preference							
Test Software		Test Preference	Test Time(Hours)	Result	Note			
PASSMARK Bru	ınIn test (9.0)	Reference below setting	12	PASS				
Test item	Loading (%)	Test preference			•			
CPU	100		Select CPU test types: General purpose instructions, Floating Point Unit instructions, Prime number test Extension instructions: MMX, 3DNow!, SSE, SSE2					
RAM	100	Default preference: RAM test mode and test patter Test: Default(Cyclic)	RAM test mode and test pattern: Standard					
Com Port(s)	100	Default preference: Detect and loopback test Send and receive timeout: 3500 Port speed: 115200 Kbits/Sec	Default preference: Detect and loopback test Send and receive timeout: 3500					
USB	100	Default preference: ISB3.0 device loopback						
Video	100	Default preference: Select video playback files: C:\\Clock.avi						
2D Graphics	100	Default preference: 2D Graphics Test: All availiable Video Memory						
3D Graphics	100	Default preference: Test window setup (Multiple monitorof testing): Number of: 1(default) Window placement: Auto placement on primary monitor (default) Window size: 300x200 pixels (default)						
LAN port 1	100	LAN port Loopback						
LAN port 2	100	LAN port Loopback	LAN port Loopback					



Stop time: - Duration: 019h 09m 01s	File View Tools Help Sensor Value Min Max Bensor Value Min Max Bensor Value Min Max Bensor Intel Core # Bensor Bensor Bensor Min Max Bensor Bensor Min Max Bensor Bensor Min Max Bensor Bensor Min Max Bensor Bensor Min Min Max Bensor Min Min Max Bensor Min Min Min Bensor Min Min Min Bensor Min Min Min Bensor Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min Min<
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RUNNING (0 Errors)	Processe Performance Apphitory Startup Users Details Services
dy 1990 Maaloo	Ethernet S 22 8 5 A Maps Ethernet S 22 8 5 A Maps Ethernet S 22 8 5 A Maps Ethernet S 20 8 5 A Maps Ethernet S 0 8 0 Kpps Ethernet Ublication S 0 8 0 Kpps 1000% 2.5 3 5 8 5.1 Maps 1000% S 10 0 Kpps 1000% S 20 8 5 0 Kpps 1000% Ethernet 1000% S 30 8 5.1 Maps 136 6 CHz GPU 0 Visualization: Ethernet 1 Cache Ethernet 1 Cache Ethernet 1 Cache Ethernet 0 19:23:08 Ethernet 1 Cache



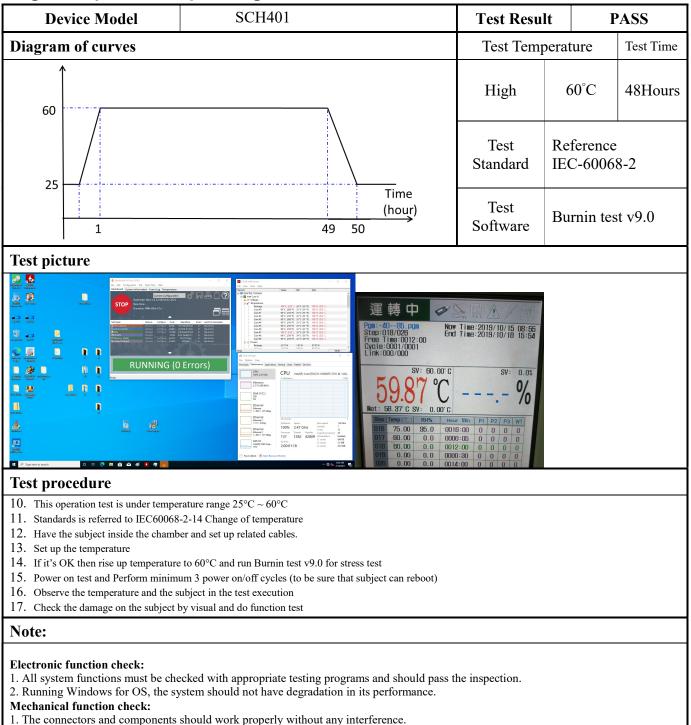


Mechanical function check:

- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



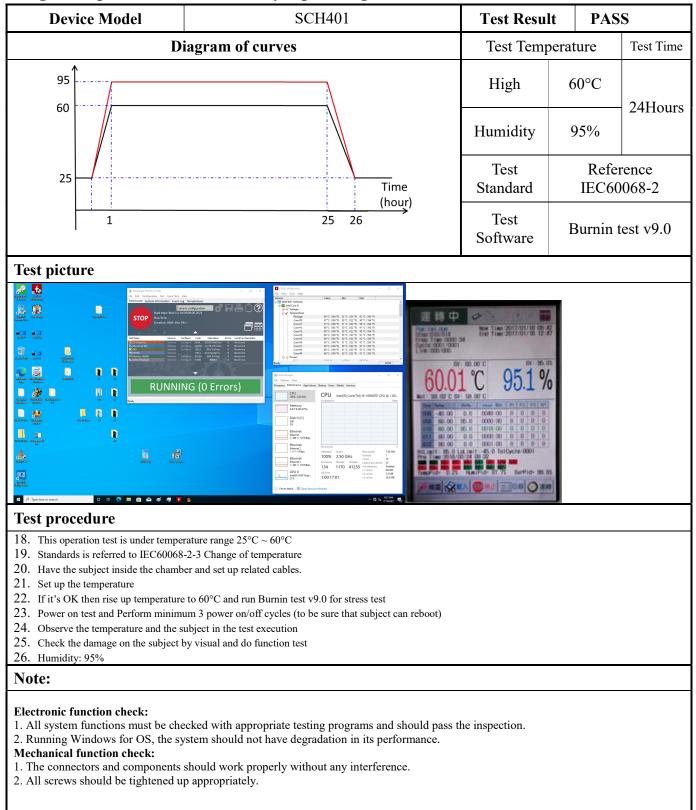
7. High Temperature Operating Test



- 2. All groups should be tightened up appropriately
- 2. All screws should be tightened up appropriately.

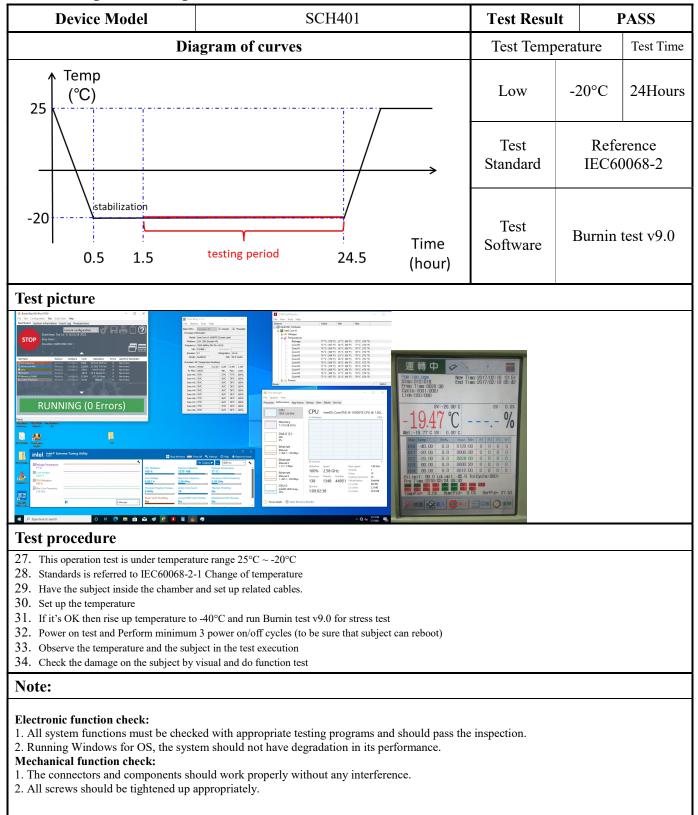


8. High Temperature and Humidity Operating Test





9. Low Temperature Operation Test





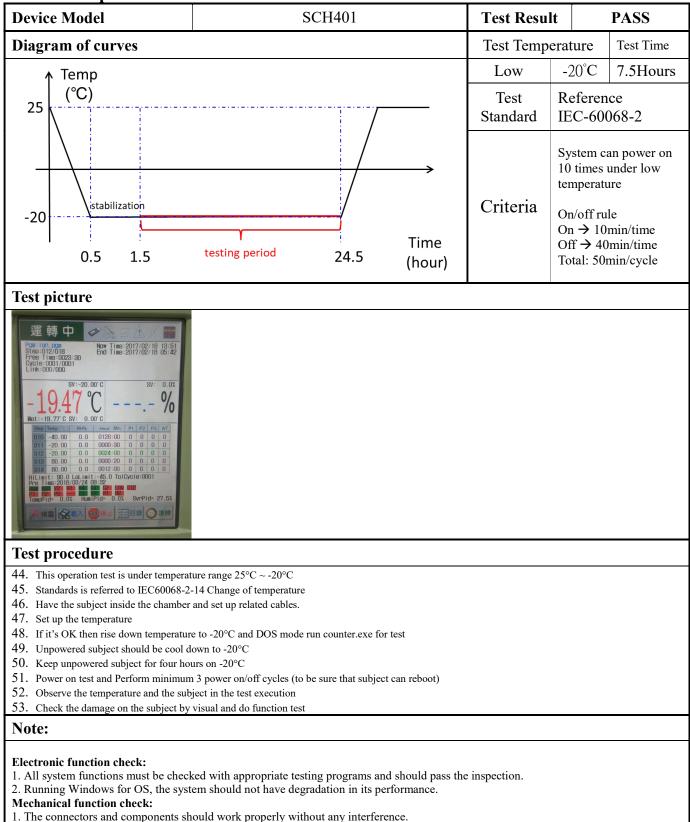
10. High Temperature Power ON/OFF Test

Device Model	SCH401	Test Resul	t	PASS
Dia	Test Temp	erature	Test Time	
1		High	60°C	8.33Hours
60		Test Standard	Reference IEC60068-2	
25			System can power on 10 times under high temperature	
1	Time (hour) 49 50	criteria	On/off rule On \rightarrow 10 minute/time Off \rightarrow 40 minute/time Total: 50 minute/cycle	
Test picture				
$\frac{1}{100} \frac{1}{100} \frac{1}$				
Test procedure				
40. Unpowered subject should be burn	2-2 Change of temperature er and set up related cables. to 60°C and DOS mode run counter.exe for test up to 70°C um 3 power on/off cycles (to be sure that subject can reboot ubject in the test execution)		
Note:				
2. Running Windows for OS, the sy Mechanical function check:	cked with appropriate testing programs and should p stem should not have degradation in its performance should work properly without any interference.			

2. All screws should be tightened up appropriately.



11. Low Temperature Power ON/OFF Test



- 1. The connectors and components should work property with
- 2. All screws should be tightened up appropriately.



12. Thermal Measurement

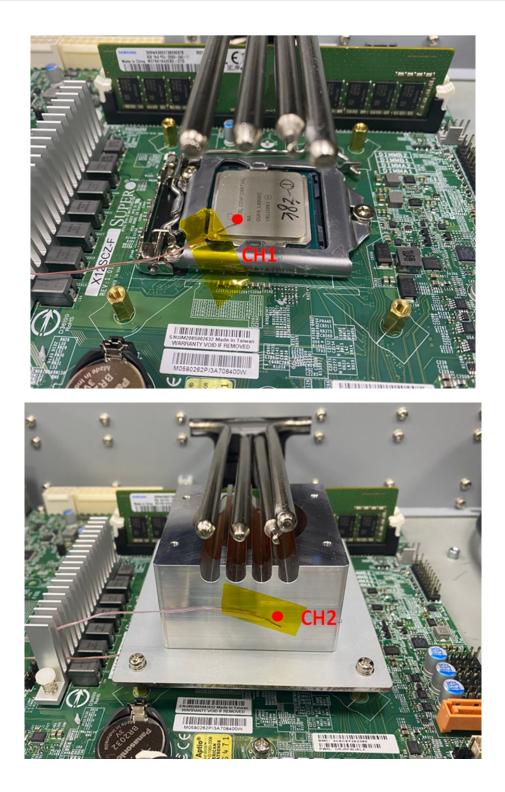
Test Purpose	The purpose of performing thermal profile test is to identify potential thermal problem of the EUT. And it is to aid products in reliability assessment considering that semiconductor failure rates rise rapidly with increasing junction temperature In case of systems cooling, patterns will vary with stacking choices, temperature/thermal mapping can aid in the development of optimum tacking arrangements							
Test Equipment	. KSON THS-B4T-150 Chamber 2. YOKOGAWA MV1000, Thermometer (FLUKE50D K/J) 3. Infrared thermal imaging camera Model TVS-200EX							
Quantity Tested	Minimum 1 Set							
Test Software	Passmark Burn-In Test under Windows 10							
Test Procecedure	 Thermal pre-scan measurement: Temperature: 24~26°C/40~60%RH Capture thermal IR photo for whole boards after the EUT execute passmark burn-in test with 100% lading during 1 hour at least. Thermal actual measurement: a. Select the test points according to the IR photo and attach thermocouples to the hot points b. Put the EUT in thermal chamber and set the temperature profile of as test specification c. Turn on the thermal chamber and power on the EUT to enter windows environment to run Max Power Test + 3DMARK 2003 application program d. After the EUT executing the test software for 4 hours, record thermal maximum value for each thermocouples point. e. Turn off the thermal chamber and EUT f. Verify and check recorded figure of each components to its' operating temperature range listed in specification/approval sheet of each measured component 							
Test diagram of curves	Environment defines for 8 hours Temp 70 (°C) 60 55 50 40 25 1.5 3 4.5 5 6.58 9.5 10 11.5 12 13.5 14 15.5 $16Time(hour)-10-20$							



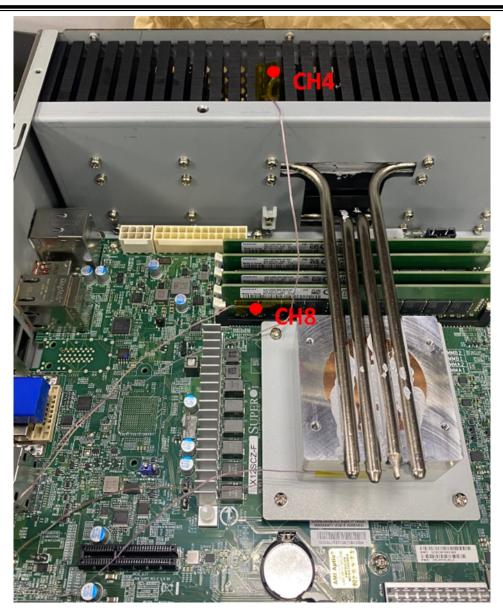


Thermal point

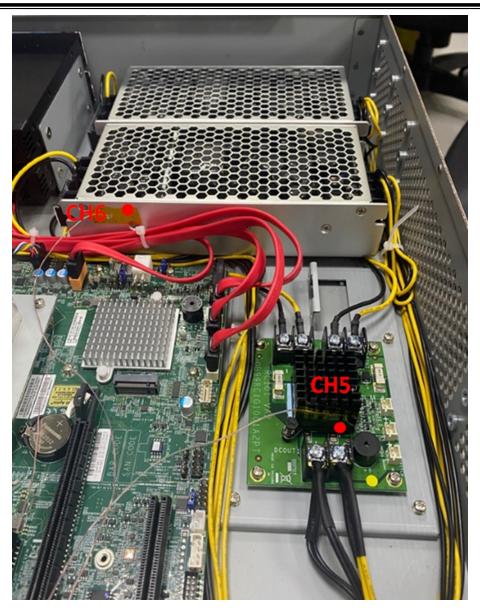




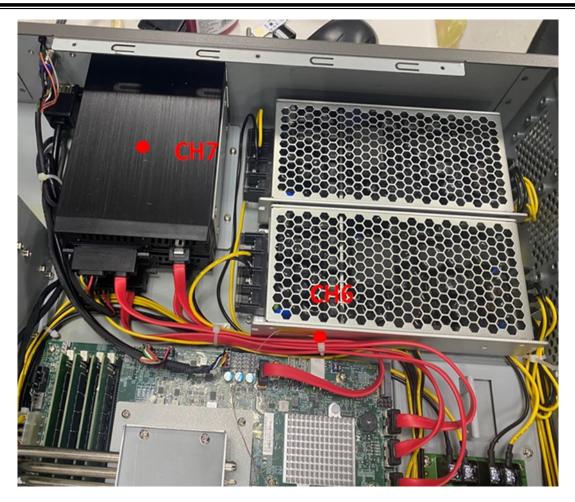














Test Result

	Point	-20°C	0°C	25℃	50℃	55℃	60℃
(CPU Frequency(GHz)	2.72	2.68	2.53	2.62	2.56	2.46
	CPU T-J (°C)	10	30	78	90	95	100
1	CPU Die	6	26.6	66	77.1	82	86.2
2	CPU Heatsink	-7	17.5	54	64.8	68	73.6
4	CPU 旁 Heatsink	-2	12.2	49.5	60	64	69.7
5	RC101	-15	7.6	46.1	56.4	58	61.1
6	POWER	-10	11.9	47.2	57.5	60	64
7	SSD	26	48.6	48.3	55.6	57	61.1
8	RAM	10	30.9	69.1	80.4	85	89.3
I2	219 LAN 1000M/100M (Mb)	917	917	908	913	916	921
12	210 LAN 1000M/100M (Mb)	945	945	948	943	944	944
	SSD 1TB (Read/Write MB)	555/478	555/482	556/485	196/164	196/167	196/162